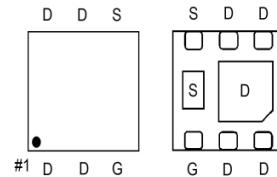
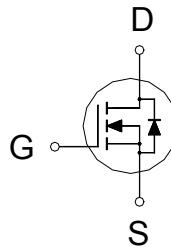


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
PB606BX
PDFN 2x2S
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	18mΩ	7.3A


G : GATE
D : DRAIN
S : SOURCE

100% RG Test , 100% UIL Test

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	7.3	A
	$T_A = 70^\circ\text{C}$		5.9	
Pulsed Drain Current ¹		I_{DM}	21	A
Avalanche Current		I_{AS}	12.8	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	8.2	mJ
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	1.5	W
	$T_A = 70^\circ\text{C}$		1	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		80	°C/W

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.75	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 6\text{A}$	19	27		$\text{m}\Omega$
		$V_{GS} = 10\text{V}, I_D = 7\text{A}$	13	18		
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10\text{V}, I_D = 7\text{A}$	31			S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		329		pF
Output Capacitance	C_{oss}			68		
Reverse Transfer Capacitance	C_{rss}			48		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		2.6		Ω
Total Gate Charge ²	$Q_g(V_{GS}=10V)$	$V_{DS} = 15V, I_D = 7A$		8.1		nC
	$Q_g(V_{GS}=4.5V)$			4.5		
Gate-Source Charge ²	Q_{gs}			1.1		
Gate-Drain Charge ²	Q_{gd}			2.4		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 15V$ $I_D \approx 7A, V_{GEN} = 10V, R_G = 6\Omega$		17		nS
Rise Time ²	t_r			17		
Turn-Off Delay Time ²	$t_{d(off)}$			37		
Fall Time ²	t_f			18		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				1.5	A
Forward Voltage ¹	V_{SD}	$I_F = 7A, V_{GS} = 0V$			1	V
Reverse Recovery Time	t_{rr}	$I_F = 7A, dI_F/dt = 100A/\mu S$		9.6		nS
Reverse Recovery Charge	Q_{rr}			2.9		nC

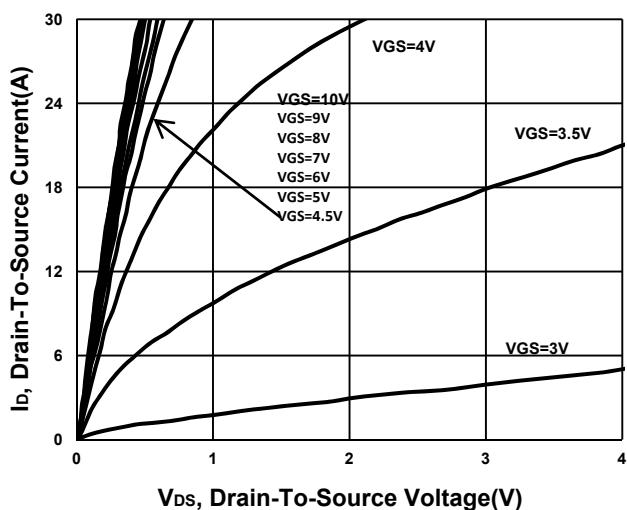
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

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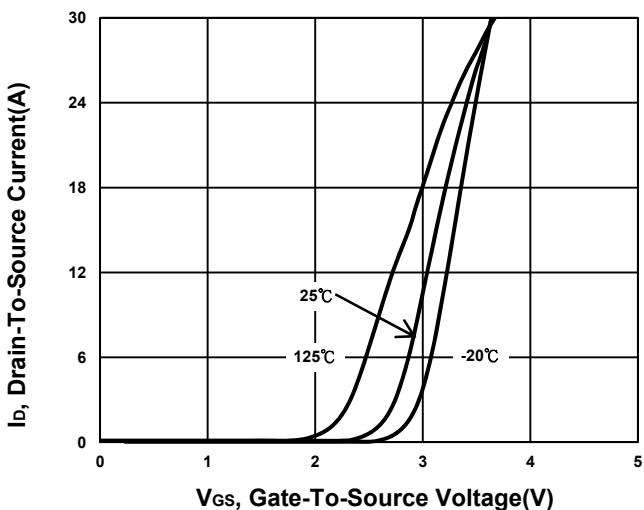
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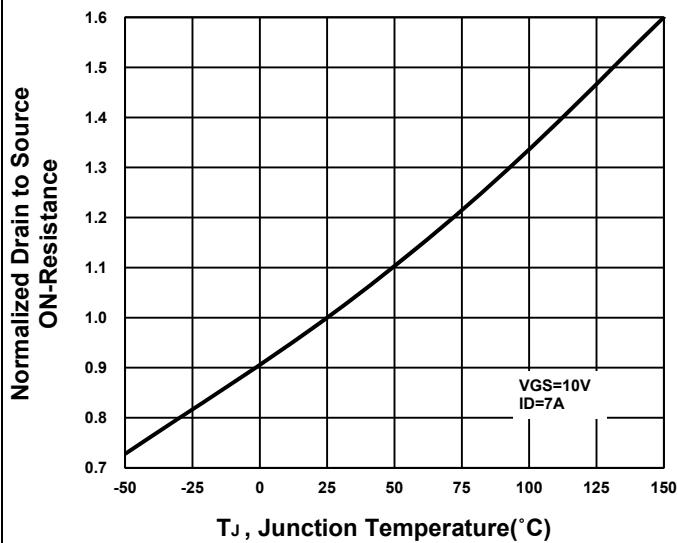
Output Characteristics



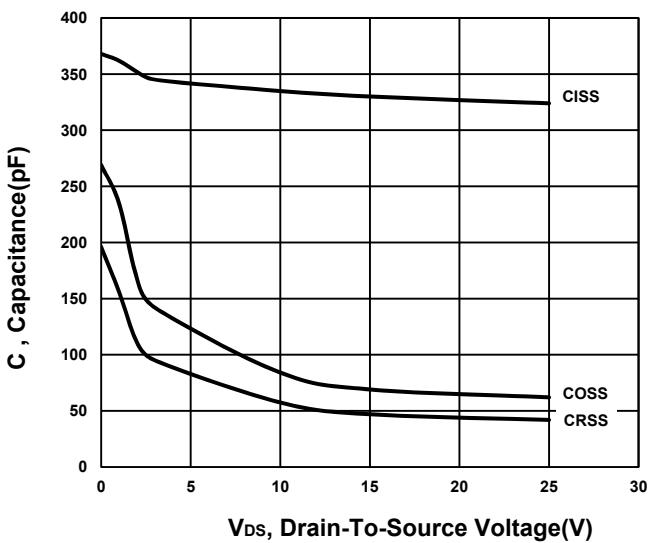
Transfer Characteristics



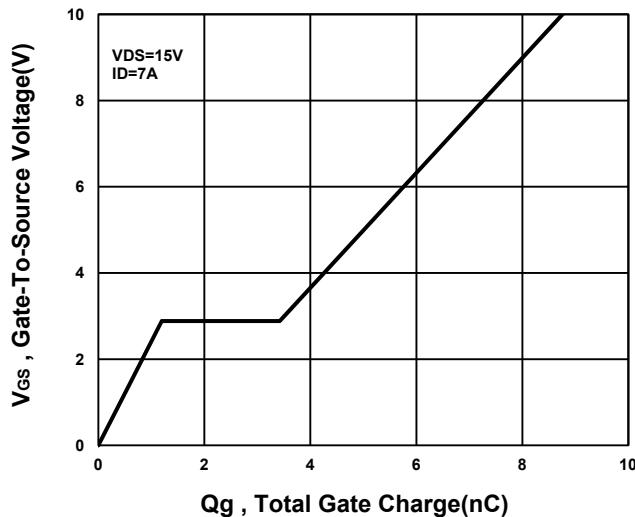
On-Resistance VS Temperature



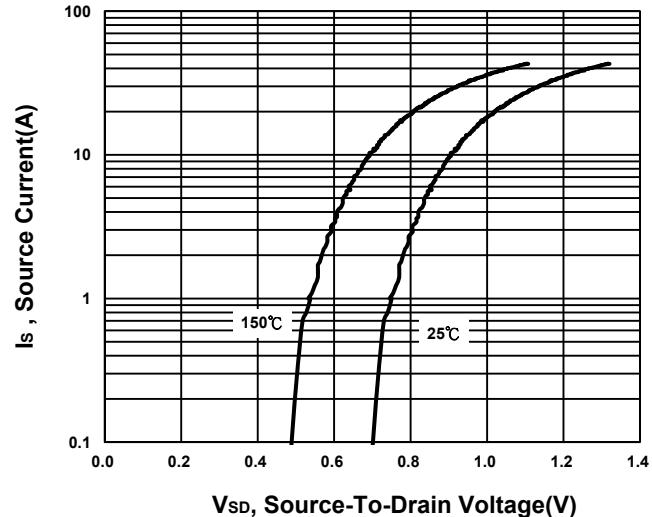
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



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